

QFET™

FQB10N60C / FQI10N60C

600V N-Channel MOSFET

General Description

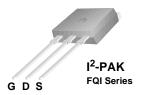
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

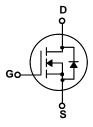
This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switched mode power supplies, active power factor correction, electronic lamp ballasts based on half bridge topology.

Features

- 9.5A, 600V, $R_{DS(on)} = 0.73\Omega @V_{GS} = 10 V$
- Low gate charge (typical 44 nC)
- Low Crss (typical 18 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability







Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQB10N60C / FQI10N60C	Units
V _{DSS}	Drain-Source Voltage	ource Voltage		V
I _D	Drain Current - Continuous (T _C = 25°	°C)	9.5	Α
	- Continuous (T _C = 10	0°C)	3.3	А
I _{DM}	Drain Current - Pulsed	(Note 1)	38	А
V _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	700	mJ
I _{AR}	Avalanche Current	(Note 1)	9.5	А
E _{AR}	Repetitive Avalanche Energy	(Note 1)	15.6	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.5	V/ns
	Power Dissipation (T _A = 25°C)*		3.13	W
P_D	Power Dissipation (T _C = 25°C)		156	W
	- Derate above 25°C	1.25	W/°C	
T_J , T_{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		0.8	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient*		40	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W	

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	racteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	oltage $V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$				V
ΔBV _{DSS} / ΔΤ _J	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}$, Referenced to 25°C		0.7		V/°C
I _{DSS}	Zana Oata Walta ya Basia Oama d	V _{DS} = 600 V, V _{GS} = 0 V			1	μΑ
	Zero Gate Voltage Drain Current	V _{DS} = 480 V, T _C = 125°C			10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Cha	racteristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 4.75 A		0.6	0.73	Ω
9 _{FS}	Forward Transconductance	$V_{DS} = 40 \text{ V}, I_D = 4.75 \text{ A}$ (Note 4))	8.0		S
Dynam i C _{iss}	ic Characteristics Input Capacitance	V 25 V V 0 V		1570	2040	pF
Coss	Output Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		166	215	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1.0 1011 12		18	24	pF
	na Charactaristics					
t _{d(on)}	ng Characteristics Turn-On Delay Time			23	55	ns
t _r	Turn-On Rise Time	$V_{DD} = 300 \text{ V}, I_{D} = 9.5 \text{A},$		69	150	ns
t _{d(off)}	Turn-Off Delay Time	$R_G = 25 \Omega$		144	300	ns
t _f	Turn-Off Fall Time	(Note 4, 5)	77	165	ns
Q _g	Total Gate Charge	V _{DS} = 480 V, I _D = 9.5A,		44	57	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = 100 \text{ V}, I_D = 0.07 \text{ V},$		6.7		nC
Q _{gd}	Gate-Drain Charge	(Note 4, 5)	18.5		nC
	ource Diode Characteristics a	ad Maximum Batings		I	I.	1
l _S	Maximum Continuous Drain-Source Did				9.5	Α
I _{SM}	Maximum Pulsed Drain-Source Diode F	Forward Current			38	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 9.5 A			1.4	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V, } I_{S} = 9.5 \text{ A,}$		420		ns
Q _{rr}	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)	4.2		μС

- Notes:
 1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 14.2mH, I_{AS} = 9.5 A, V_{DD} = 50V, R_G = 25 Ω, Starting T_J = 25°C 3. I_{SD} ≤ 9.5A, di/dt ≤ 200A/μs, V_{DD} ≤ BV_{DSS}, Starting T_J = 25°C 4. Pulse Test : Pulse width ≤ 300μs, Duty cycle ≤ 2% 5. Essentially independent of operating temperature

Typical Characteristics

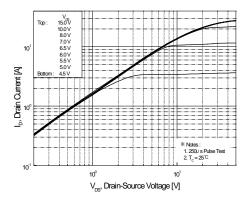


Figure 1. On-Region Characteristics

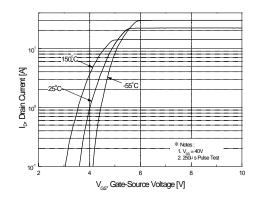


Figure 2. Transfer Characteristics

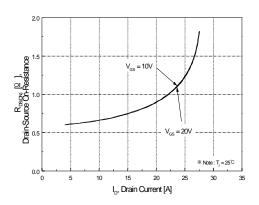


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

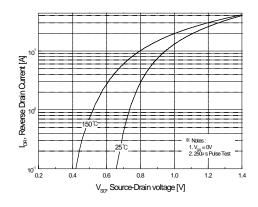


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

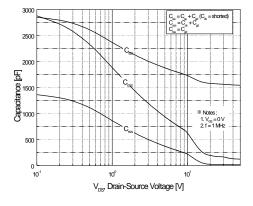


Figure 5. Capacitance Characteristics

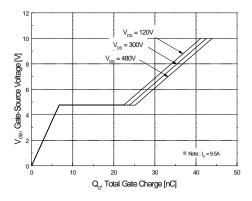
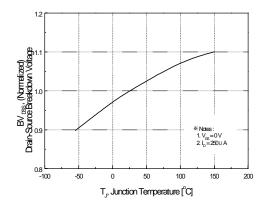


Figure 6. Gate Charge Characteristics

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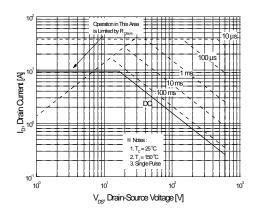
Typical Characteristics (Continued)



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Figure 7. Breakdown Voltage Variation vs Temperature





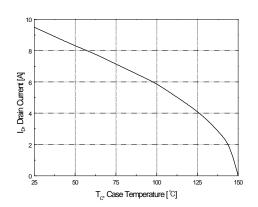


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs Case Temperature

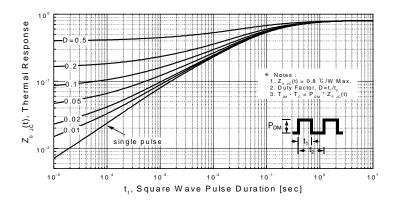
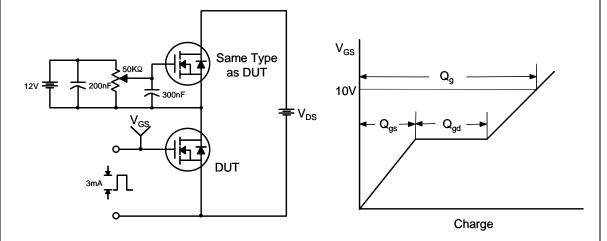


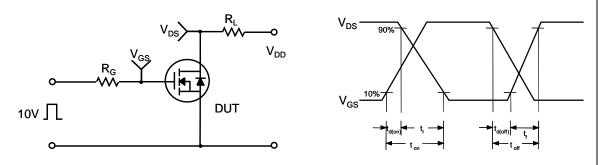
Figure 11. Transient Thermal Response Curve

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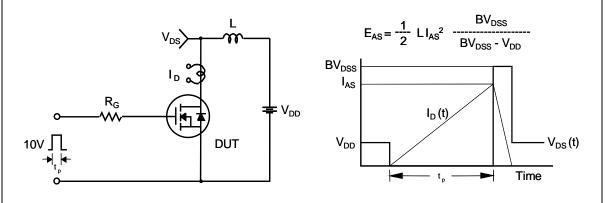
Gate Charge Test Circuit & Waveform



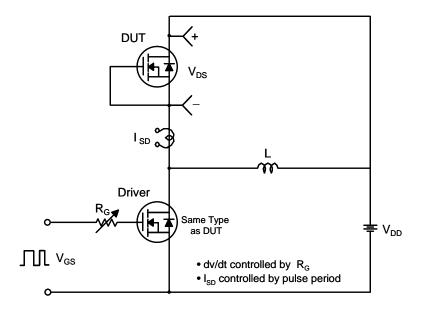
Resistive Switching Test Circuit & Waveforms

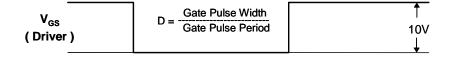


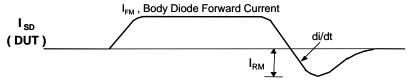
Unclamped Inductive Switching Test Circuit & Waveforms



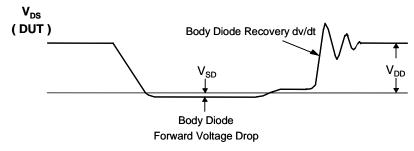
Peak Diode Recovery dv/dt Test Circuit & Waveforms

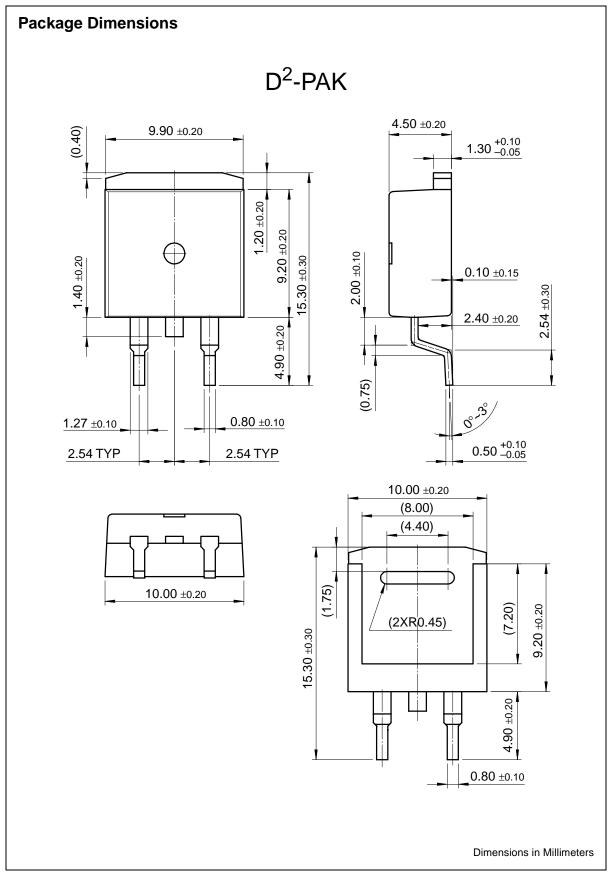


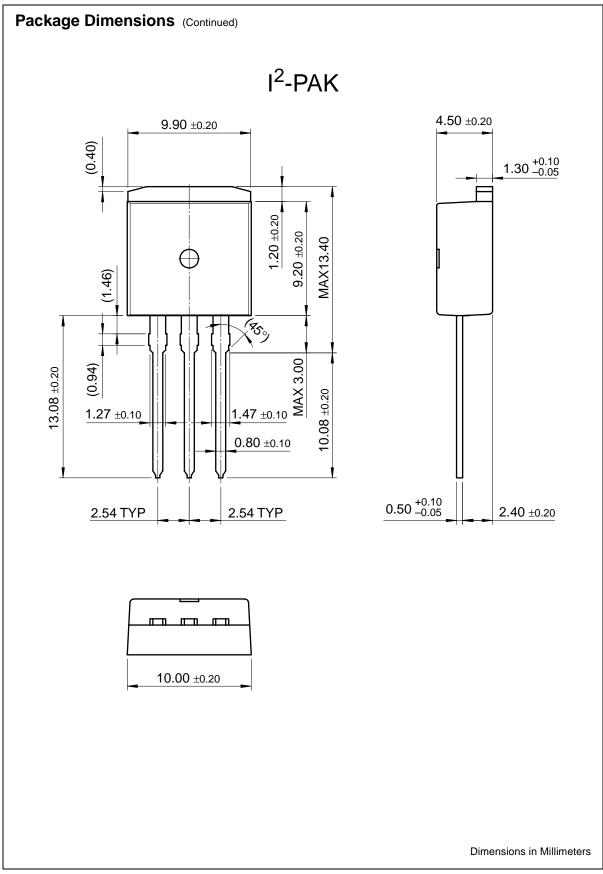




Body Diode Reverse Current







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FQI10N60C

600V N-Channel Advance Q-FET C-Series

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General description

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Features

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- Fast switching
- 100% avalanche tested
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Product status/pricing/packaging



	Product	Product status	Pb-free Status	Pricing*	Package type	Leads	Packing method	Package Marking Convention**
1								

FQI10N60CTU	Full Production	Full Production	\$1.54	TO-262(I2PAK)	3	RAIL	Line 1: \$Y (Fairchild logo) & Z (Asm. Plant Code) & 4 (4-Digit Date Code) Line 2: FQI Line 3: 10N60C
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^{*} Fairchild 1,000 piece Budgetary Pricing

** A sample button will appear if the part is available through Fairchild's on-line samples program. If there is no sample button, please contact a Fairchild distributor to obtain samples



Indicates product with Pb-free second-level interconnect. For more information click here.

Package marking information for product FQI10N60C is available. Click here for more information.

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Qualification Support

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FQI10N60CTU

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